

# RJK0389DPA

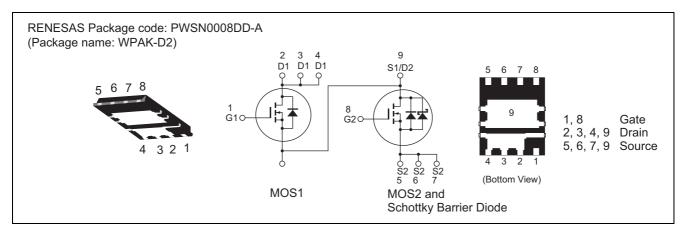
## Silicon N Channel Power MOS FET with Schottky Barrier Diode High Speed Power Switching

REJ03G1722-0300 Rev.3.00 Dec 03, 2008

## **Features**

- Low on-resistance
- Capable of 4.5 V gate drive
- High density mounting
- Pb-free
- Halogen-free

## **Outline**



## **Absolute Maximum Ratings**

 $(Ta = 25^{\circ}C)$ 

		Ra		
Item	Symbol	MOS1	MOS2	Unit
Drain to source voltage	V <sub>DSS</sub>	30	30	V
Gate to source voltage	V <sub>GSS</sub>	±20	±20	V
Drain current	I <sub>D</sub>	15	20	Α
Drain peak current	I <sub>D(pulse)</sub> Note1	60	80	Α
Reverse drain current	I <sub>DR</sub>	15	20	Α
Avalanche current	I <sub>AP</sub> Note 2	8	11	Α
Avalanche energy	E <sub>AR</sub> Note 2	6.4	12.1	mJ
Channel dissipation	Pch Note3	10	10	W
Channel temperature	Tch	150	150	°C
Storage temperature	Tstg	-55 to +150	-55 to +150	°C

Notes: 1. PW  $\leq$  10  $\mu$ s, duty cycle  $\leq$  1%

- 2. Value at Tch = 25°C, Rg  $\geq$  50  $\Omega$
- 3.  $Tc = 25^{\circ}C$

## **Electrical Characteristics**

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 $(Ta = 25^{\circ}C)$ 

Item	Symbol	Min	Тур	Max	Unit	Test Conditions
Drain to source breakdown voltage	$V_{(BR)DSS}$	30	_	_	V	$I_D = 10 \text{ mA}, V_{GS} = 0$
Gate to source leak current	I <sub>GSS</sub>	_	_	±0.1	μΑ	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0$
Zero gate voltage drain current	I <sub>DSS</sub>	_	_	1	μΑ	$V_{DS} = 30 \text{ V}, V_{GS} = 0$
Gate to source cutoff voltage	$V_{GS(off)}$	1.2	_	2.5	V	$V_{DS} = 10 \text{ V}, I_D = 1 \text{ mA}$
Static drain to source on state	R <sub>DS(on)</sub>	_	8.2	10.7	mΩ	$I_D = 7.5 \text{ A}, V_{GS} = 10 \text{ V}^{\text{Note4}}$
resistance	R <sub>DS(on)</sub>	_	11.8	16.5	mΩ	$I_D = 7.5 \text{ A}, V_{GS} = 4.5 \text{ V}^{\text{Note4}}$
Forward transfer admittance	y <sub>fs</sub>	_	32	_	S	$I_D = 7.5 \text{ A}, V_{DS} = 10 \text{ V}^{\text{Note4}}$
Input capacitance	Ciss	_	860	_	pF	V <sub>DS</sub> = 10 V
Output capacitance	Coss	_	165	_	pF	$V_{GS} = 0$
Reverse transfer capacitance	Crss	_	53	_	pF	f = 1 MHz
Gate Resistance	Rg	_	4.2	_	Ω	
Total gate charge	Qg	_	6.3	_	nC	V <sub>DD</sub> = 10 V
Gate to source charge	Qgs	_	2.3	_	nC	V <sub>GS</sub> = 4.5 V
Gate to drain charge	Qgd	_	1.4	_	nC	I <sub>D</sub> = 15 A
Turn-on delay time	t <sub>d(on)</sub>	_	6.9	_	ns	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 7.5 A
Rise time	t <sub>r</sub>	_	4.1	_	ns	V <sub>DD</sub> ≅ 10 V
Turn-off delay time	t <sub>d(off)</sub>		40.8	_	ns	$R_L = 1.33 \Omega$
Fall time	t <sub>f</sub>		5.6	_	ns	$R_g = 4.7 \Omega$
Body-drain diode forward voltage	$V_{DF}$	_	0.84	1.10	V	$I_F = 15 \text{ A}, V_{GS} = 0^{\text{Note4}}$
Body-drain diode reverse	t <sub>rr</sub>	_	20	_	ns	$I_F = 15 \text{ A}, V_{GS} = 0$
recovery time						di <sub>F</sub> / dt = 100 A/μs

Notes: 4. Pulse test

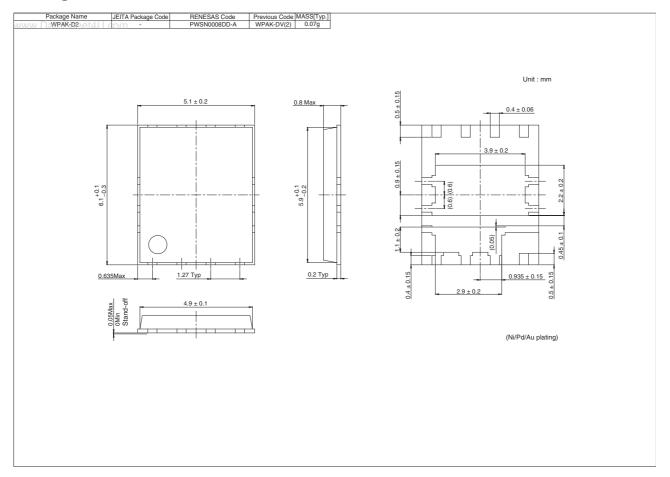
## • MOS2

 $(Ta = 25^{\circ}C)$ 

www.DataSheet4UItem	Symbol	Min	Тур	Max	Unit	Test Conditions
Drain to source breakdown voltage	V <sub>(BR)DSS</sub>	30	_	_	V	$I_D = 10 \text{ mA}, V_{GS} = 0$
Gate to source leak current	I <sub>GSS</sub>	_	_	±0.1	μΑ	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0$
Zero gate voltage drain current	I <sub>DSS</sub>	_	_	1	mA	$V_{DS} = 30 \text{ V}, V_{GS} = 0$
Gate to source cutoff voltage	$V_{GS(off)}$	1.2	_	2.5	V	$V_{DS} = 10 \text{ V}, I_{D} = 1 \text{ mA}$
Static drain to source on state	R <sub>DS(on)</sub>	_	6.8	8.9	mΩ	$I_D = 10 \text{ A}, V_{GS} = 10 \text{ V}^{Note4}$
resistance	R <sub>DS(on)</sub>	_	10.5	14.7	mΩ	$I_D = 10 \text{ A}, V_{GS} = 4.5 \text{ V}^{\text{Note4}}$
Forward transfer admittance	y <sub>fs</sub>	_	38	_	S	$I_D = 10 \text{ A}, V_{DS} = 10 \text{ V}^{\text{Note4}}$
Input capacitance	Ciss	_	1000	_	pF	V <sub>DS</sub> = 10 V
Output capacitance	Coss	_	240	_	pF	$V_{GS} = 0$
Reverse transfer capacitance	Crss	_	100	_	pF	f = 1 MHz
Gate Resistance	Rg	_	4.5	_	Ω	
Total gate charge	Qg	_	7.2	_	nC	V <sub>DD</sub> = 10 V
Gate to source charge	Qgs	_	2.9	_	nC	V <sub>GS</sub> = 4.5 V
Gate to drain charge	Qgd	_	2.2	_	nC	$I_D = 20 \text{ A}$
Turn-on delay time	t <sub>d(on)</sub>	_	8.5	_	ns	$V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$
Rise time	t <sub>r</sub>	_	4.0	_	ns	$V_{DD} \cong 10 \text{ V}$
Turn-off delay time	$t_{d(off)}$	_	39	_	ns	$R_L = 1.0 \Omega$
Fall time	t <sub>f</sub>	_	6.6	_	ns	$R_g = 4.7 \Omega$
Schottky Barrier diode forward voltage	V <sub>F</sub>	_	0.44	_	V	$I_F = 2 A$ , $V_{GS} = 0$ Note4
Body-drain diode reverse	t <sub>rr</sub>	_	12	_	ns	I <sub>F</sub> = 20 A, V <sub>GS</sub> = 0
recovery time						$di_F/dt = 100 A/\mu s$

Notes: 4. Pulse test

## **Package Dimensions**



## **Ordering Information**

Part No.	Quantity	Shipping Container
RJK0389DPA-00-J53	3000 pcs	Taping

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